

ABSTRACT OF THE DISCLOSURE

A test apparatus for testing an electronic device includes a pattern generating unit for generating a test pattern to test the electronic device, a reference clock generating unit for generating a reference clock, a timing generator for generating a timing signal, an output signal sampling circuit for sampling the output signal outputted by the electronic device in response to the test pattern at the timing based on the timing signal generated by the timing generator, wherein the timing generator includes a variable delay circuit unit for receiving, delaying and outputting the reference clock, and a delay control unit for controlling the delay amount of the variable delay circuit unit, and the delay control unit controls the delay amount based on the basic timing data and the variable delay amount which is smaller than the basic timing data.